

INFORMATION DISCLOSURE STATEMENT

FORM PTO 1449 (modified)			ATTY DOCKET NO. 2005_1045A		SERIAL NO. 10/540,399		
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			APPLICANT Ryouichi TAKAYAMA et al.				
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			FILING DATE February 22, 2006		GROUP 2817		
Date Submitted to PTO: May 29, 2008							
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	6,037,847	3-14-00	Ueda et al.			
	AB	5,302,877	4-12-94	Sato et al.			
	AC						
	AD						
	AC						
	AF						
	AC						
	AH						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	BA	0 744 830	11-27-96	Europe			X
	BB	0 734 120	9-25-96	Europe			X
	BC	5-259802	10-8-93	Japan			abstract and corresponds to AB
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
	CA	Supplementary European Search Report issued March 26, 2008 in European Application No. EP 03 78 2874					
	CB	Kengo Asai et al., "Experimental and Theoretical Investigation for Temperature Characteristics and Propagation Losses of SAWs on $\text{SiO}_2/\text{Al}/\text{LiTaO}_3$ ", IEEE Ultrasonics Symposium, November 8, 2002 - November 11, 2002, pages 235-238					
	CC	Fred S. Hickernell, "The Application of Dielectric Thin Films to Enhance the Properties of SAW Devices", IEEE MTT-S International Microwave Symposium Digest, Vol. 1, May 20, 2001 - May 25, 2001, pages 363-366					
	CD	Osamu Kawachi et al., "Optimal Cut for Leaky SAW on LiTaO_3 for High Performance Resonators and Filters", IEEE Transactions on Ultrasonics, Ferroelectrics and Frequency Control, Vol. 48, No. 5, September 2001, pages 1442-1448					
	CE	Kazuhiko Yamanouchi et al., "High Temperature Stable Ghz-Range Low-Loss Wide Band Transducers and Filter Using $\text{SiO}_2/\text{LiNbO}_3/\text{LiTaO}_3$ ", IEEE Transactions on Ultrasonics, Ferroelectrics and Frequency Control, Vol. 42, No. 3, May 1995, pages 392-396					
EXAMINER				DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.